## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination PAN ET AL. | Examiner | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0047284	03-2004	Eidson, Donald Brian	370/203
*	В	US-7,139,320	11-2006	Singh et al.	375/260
*	С	US-2004/0131010	07-2004	Pan et al.	370/210
*	D	US-5,457,462	10-1995	Mitsumoto et al.	342/93
*	E	US-6,122,703	09-2000	Nasserbakht, Mitra	711/5
*	F	US-7,266,168	09-2007	Kwak et al.	375/347
*	G	US-6,320,897	11-2001	Fattouche et al.	375/130
*	н	US-6,192,068	02-2001	Fattouche et al.	375/130
*	ı	US-6,826,240	11-2004	Thomas et al.	375/340
*	J	US-6,925,112	08-2005	Morejon et al.	375/222
	к	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					,
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	U						
	٧						
	w						
	x						

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